

Product Name: Smart Phone	Report No: ITEZA2-202400107RF7
Product Model: Blade10 Pro, Blade10, Blade10 Ultra, Blade10 S, Blade10 E, Blade10 SE, Blade10 Plus, Blade10 Max, Blade10 Power	Security Classification: Open
Version: V1.0	Total Page: 53

TIRT Testing Report

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RF TEST REPORT

FCC ID: 2AX4YBLADE10PRO

According to

FCC CFR Title 47 Part 2 FCC CFR Title 47 Part 22 Subpart H FCC CFR Title 47 Part 24 Subpart E FCC CFR Title 47 Part 27 Subpart C FCC CFR Title 47 Part 90 Subpart S ANSI C63.26:2015 KDB 971168 D01 Power Meas License Digital Systems v03r01

Applicant:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No. 22, Longhua New District, Shenzhen, China
Manufacturer:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No. 22, Longhua New District, Shenzhen, China
Sample No:	1000032108
Product Name:	Smart Phone
Brand Name:	DOOGEE
Model No.:	Blade10 Pro, Blade10, Blade10 Ultra, Blade10 S, Blade10 E, Blade10 SE, Blade10 Plus, Blade10 Max, Blade10 Power
Test No.:	Blade10 Pro

Date of Receipt:	2024/04/23
Date of Test:	2024/04/23~2024/05/22
Issued Date:	2024/05/27
Testing Lab:	TIRT

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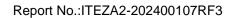




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History of this test report Original Report Issue Date: 2024.05.27

• No additional attachment

 \circ Additional attachments were issued following record

Attachment No.	Issue Date	Description



1 TEST SUMMARY		
Test Item	Section in CFR 47	Result
	Part 1.1307	Pass*(Please refer to
RF Exposure (SAR)	Part 2.1093	SAR Report)
	Part 2.1046	
	Part 22.913(a)	
	Part 24.232(b)	
RF Output Power	Part 27.50(b)	Pass
KF Oulput Fower	Part 27.50(c)	F 855
	Part 27.50(d)	
	Part 27.50(h)	
	Part 90.635	
	Part 2.1046	
Book To Average Ratio	Part 22.913(d)	Pass
Peak-To-Average Ratio	Part 24.232 (d)	Fass
	Part 27.50(d)	
Modulation Characteristics	Part 2.1047	N/A
	Part 2.1049	
00% & 20 dD Occurried Development	Part 22.917	Deee
99% & -26 dB Occupied Bandwidth	Part 24.238	Pass
	Part 27.53(a)	
	Part 2.1051	
	Part 22.917	
	Part 24.238	
Spurious Emissions at Antonna Terminal	Part 27.53(c)(f)	Pass
Spurious Emissions at Antenna Terminal	Part 27.53(g)	F 855
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1053	
	Part 22.917	
	Part 24.238	
Field Strength of Spurious Radiation	Part 27.53(c)(f)	Pass
	Part 27.53(g)	1 000
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	



	Part 2.1051	
	Part 22.917	
	Part 24.238	
Out of bond emission, Dand Edge	Part 27.53(c)(f)	Deee
Out of band emission, Band Edge	Part 27.53(g)	Pass
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1055(a)(1)(b)	
	Part 22.355	
Frequency stability vs. temperature	Part 24.235	Pass
	Part 27.54	
	Part 90.213	
	Part 2.1055(d)(1)(2)	
	Part 22.355	
Frequency stability vs. voltage	Part 24.235	Pass
	Part 27.54	
	Part 90.213	

Note: 1. Pass: The EUT complies with the essential requirements in the standard.

2. The conclusion of this test report is judged by actual test data without considering measurement uncertainty.



2 GENERAL INFORMATION

2.1 GENERAL DESCRIPTION OF EUT

Description of Device (I EUT Name	UT) : Smart Phone
Model No.	 Blade10 Pro, Blade10, Blade10 Ultra, Blade10 S, Blade10 E, Blade10 SE, Blade10 Plus, Blade10 Max, Blade10 Power
DIFF.	¹ There is no difference except the name of the model. All tests are made with
	the Blade10 Pro model.
Power supply	DC 3.87V from battery or DC5V from adapter
Support Bands	: LTE Band 2/4/5/7/19/25/26/38//41/66
Channel Bandwidth TX Frequency	 LTE Band 2: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 4: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 5: 1.4MHz, 3MHz, 5MHz, 10MHz LTE Band 7: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 19: 5MHz, 10MHz, 15MHz LTE Band 25: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 26: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz LTE Band 26: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz LTE Band 38: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 41: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz LTE Band 5: 824 ~ 849 MHz LTE Band 5: 824 ~ 849 MHz LTE Band 19: 830 ~845MHz LTE Band 25: 1850 MHz ~ 1915 MHz LTE Band 26: 814 MHz ~ 849 MHz LTE Band 38: 2570 MHz ~ 2620 MHz LTE Band 41: 2496MHz ~ 2690MHz LTE Band 41: 2496MHz ~ 2690 MHz LTE Band 66: 1710 MHz ~ 1780 MHz
Modulation type Antenna Type	 QPSK, 16QAM PIFA antenna, LTE Band 2: Maximum Gain is 0.67dBi. LTE Band 4: Maximum Gain is 0.13dBi. LTE Band 5: Maximum Gain is -4.1dBi. LTE Band 7: Maximum Gain is -4.1dBi. LTE Band 19: Maximum Gain is -4.1dBi. LTE Band 25: Maximum Gain is 0.55dBi. LTE Band 26: Maximum Gain is -4.1dBi. LTE Band 38: Maximum Gain is -1.6dBi. LTE Band 38: Maximum Gain is -1.6dBi. LTE Band 66: Maximum Gain is 0.13dBi. Antenna information is provided by applicant. There is WWAN diversity antenna inside the product, which is only for receiving function.
Software version	DOOGEE-Blade10Pro-EEA-Android14.0-20240512
Hardware version	SC6020LU-MB-1.0.1-20240411
Remark 1: The worst-ca	se simultaneous transmission configuration was evaluated with no non-compliance
found. Results in this re	port are only for 4G function, and there is no other transmitter involved.



2.2 RELATED SUBMITTAL(S) / GRANT (S)

This submittal(s) (test report) is filing to comply with Section Part 22 subpart H and Part 24 subpart E of the FCC CFR 47 Rules.

2.3 TEST FACILITY

Company:	Beijing TIRT Technology Service Co.,Ltd Shenzhen
Address:	104 Building C, Xinmingsheng Industrial Park No.132, Zhangge Old Village East Zone, Zhangge Community, Fucheng Street, Longhua District, Shenzhen, Guangdong, P. R. China
CNAS Registration Number:	CNAS L14158
A2LA Registration Number:	6049.01
FCC Accredited Lab.Designation Number:	CN1366
FCC Test Firm Registration Number:	820690
Telephone:	+86-0755-27087573

2.4 ACCESSORIES OF DEVICE (EUT)

Accessories	Adapter
Manufacturer	/
Model	DGCDQ-BC023-02
	Input: AC100-240V~ 50/60Hz 0.35A Max
Ratings	Output: 5.0V-2.0A, 10.0W Power: 10.0W Max

2.5 TESTED SUPPORTING SYSTEM DETAILS

No.	Description	Manufacturer	Model	Serial Number	Certification or SDoC
1	N/A	N/A	N/A	N/A	N/A

2.6 TEST CONDITIONS

Items	Required	Actual	
Temperature range:	15-35℃	24°C	
Humidity range:	25-75%	56%	
Pressure range:	86-106kPa	98kPa	



2.7 MEASUREMENT UNCERTAINTY

Uncertainty				
Parameter	Uncertainty			
Occupied Channel Bandwidth	±142.12 KHz			
RF power conducted	±0.74 dB			
RF power radiated	±3.25dB			
Spurious emissions, conducted	±1.78dB			
Spurious emissions, radiated (9KHz~30MHz)	±2.56dB			
Spurious emissions, radiated (30MHz \sim 1GHz)	±4.6dB			
Spurious emissions, radiated (Above 1GHz)	±4.9dB			
Conduction Emissions(150kHz~30MHz)	±3.1 dB			
Humidity	±4.6%			
Temperature	±0.7°C			
Time	±1.25%			



3 TEST INSTRUMENTS LIST

Name of Equipment	Manufacturer	Model Number	Serial Number	Last	Due
Name of Equipment	Manuacturer			Calibration	Calibration
EMI Receiver	Rohde&Schwarz	ESIB 40	YH-TIRT-SAC-966 -20220911	2024/01/05	2025/01/04
Integral Antenna	Schwarzbeck	VULB 9163	01314	2022.12.11	2024.12.10
Integral Antenna	Rohde&Schwarz	HF907	RSM2991424	2022.12.11	2024.12.10
Preamplifier	Emtrace	RP01A	'02017	2024/01/05	2025/01/04
Preamplifier	Schwarzbeck	BBV9744	00143	2024/01/05	2025/01/04
Loop Antenna	ZHINAN	ZN30900A	12024	2024/01/05	2025/01/04
Exposure Level Tester	narda	ELT-400	N-0925	2024/01/05	2025/01/04
Horn Antenna	Schwarzbeck	BBHA9170	00956	2024/01/05	2025/01/04
RF Cable	/	LMR400UF-NMNM-7. 0M	/	2024/01/05	2025/01/04
RF Cable	/	SFT2050PUR-NMNM -7.0M	/	2024/01/05	2025/01/04
EMI Receiver	Rohde&Schwarz	ESR7	1316.3003K07-10 2611-mk	2023/11/02	2024/11/01
LISN	Rohde&Schwarz	ENV216	3560.655.12-1029 15-Bp	2023/11/02	2024/11/01
ISN	Schwarzbeck	ENY81	1309.8510.03	2024/01/05	2025/01/04
ISN	Schwarzbeck	ENY81-CAT6	1309.8526.03-101 976-kh	2024/01/05	2025/01/04
RF Cable	\	SFT2050PUR-NMNM -2.0M	\	2024/01/05	2025/01/04
CMW500	ROHDE&SCHWARZ	CMW500	120434	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSU26	200732	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSV40-N	101722	2024/01/05	2025/01/04
vector Signal Generator	KEYSIGHT	N5182B	MY56200458	2024/01/05	2025/01/04
vector Signal Generator	HEWLETT PACKARD	83752A	3610A02458	2024/01/05	2025/01/04
Filter	HEWLETT PACKARD	JS0806-F	19K8060209	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8821C	SN6262170409	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8000A	SN6262166782	2024/01/05	2025/01/04



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4 SYSTEM TEST CONFIGURATION

4.1 TEST MODE

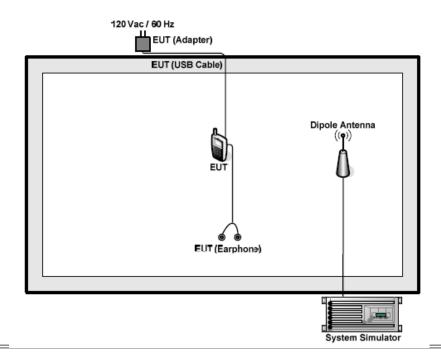
During all testing, EUT is in link mode with base station emulator at maximum power level. The spurious emission measurements were carried out in semi-anechoic chamber with 3-meter test range, and EUT is rotated on three test planes to find out the worst emission.

Test modes					
Band	Radiated	Conducted			
LTE Band 2	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 4	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 5	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 7	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 19	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 25	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 26	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 38	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 41	QPSK link, 16QAM link	QPSK link, 16QAM link			
LTE Band 66	QPSK link, 16QAM link	QPSK link, 16QAM link			

Note: Antenna port conducted and radiated test items were performed according to KDB 971168 D01 Power Meas License Digital Systems v03r1 with maximum output power.

Radiated measurements were performed with rotating EUT in different three orthogonal test planes to find the maximum emission.

4.2 CONFIGURATION OF TESTED SYSTEM





Test Requirement:	Part 2.1046,Part 22.913(a), Part 24.232(c), Part 27.50(b), Part 27.50(c), Part 27.50(d), Part 27.50(h), Part 90.635	
Test Method:	ANSI C63.26:2015	
Limit:	LTE Band 2: 2W	
	LTE Band 4: 1W	
	LTE Band 5/19: 7W	
	LTE Band 7: 2W	
	LTE Band 25: 2W	
	LTE Band 26: 100W	
	LTE Band 38: 2W	
	LTE Band 41: 2W	
	LTE Band 66: 1W	
Test setup:	EUT Splitter Tester	
	Power meter Note: Measurement setup for testing on Antenna connector	
Test Procedure:	1. The transmitter output port was connected to base station.	
	2. The RF output of EUT was connected to the power meter by RF	
	cable and attenuator, the path loss was compensated to the res	
	for each measurement.	
	3. Set EUT at maximum power through base station.	
	4. Select lowest, middle, and highest channels for each band and	
	different modulation.	
	5. Measure the maximum burst average power.	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	

Note: Please refer to Appendix A of the Appendix Test Data.



Test Requirement:	Part 22.913(d), FCC part24.232(d) and FCC part27.50(d)(5)	
Test Method:	ANSI C63.26:2015	
Test Limit:	Used complementary cumulative distribution function (CCDF) of analyzer to determine that PAPR will not exceed 13 dB for more than 0.1 percent of the time	
Test setup:	EUT Splitter Communication Tester	
Tast Drass duras	 Note: Measurement setup for testing on Antenna connector The testing follows FCC KDB 971168 D01 v03r01 Section 5.7 The EUT was connected to spectrum and system simulator via a power divider Using the CCDF measurement ofspectrum analyzer; Set RBW≥OBW or specified reference bandwidth; Set the number of counts to a value that stabilizes the measured CCDF curve; Set the measurement interval as 1ms Record the maximum PAPR level associated with a probability of 0.1%. 	
Test Procedure:		
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	

Note: Please refer to Appendix B of the Appendix Test Data.



Test Requirement:	FCC part22.913(a), FCC part24.232(b) and FCC part27.53(a), FCC part 90.209	
Test Method:	ANSI C63.26:2015	
Test setup:	EUT Splitter Communication Tester	
	Note: Measurement setup for testing on Antenna connector	
Test Procedure:	 1.The EUT's output RF connector was connected with a short cable to the spectrum analyzer, set center frequency to channel center frequency. 2.RBW was set to about 1%-5% of emission OBW, VBW≥ 3 X RBW. 3.Set spectrum analyzer detection mode to peak, and the trace mode to max hold. 4. Use the 99% OBW function, The 99% power OBW can be found on the plot, determine the "-26dB amplitude" as equal to reference value -26dB. 	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	



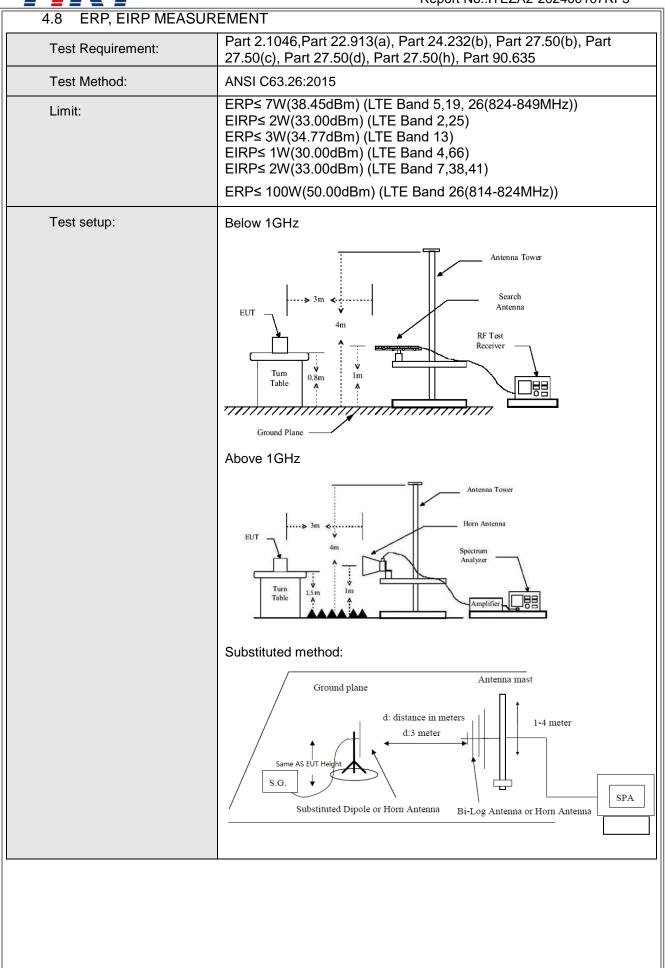
4.6 MODULATION CHARACTERISTIC

According to FCC § 2.1047(d), Part 24E & Part 27 there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.



4.7 OUT OF BAND EMISSION AT ANTENNA TERMINALS		
Test Requirement:	Part 2.1051 Part 22.917 Part 24.238 Part 27.53(c)(f) Part 27.53(g) Part 27.53(h) Part 27.53(m) Part 90.691	
Test Method:	ANSI C63.26:2015	
Limit:	 ≤ -13dBm(LTE Band5,19, 26(824-849MHz)) ≤ -13dBm(LTE Band2,25) ≤ -13dBm(LTE Band4,66) ≤ -25dBm(LTE Band 7, 38, 41) ≤ -13dBm(LTE Band26(814-824MHz)) 	
Test setup:	EUT Splitter Communication Tester Filter SPA	
	Note: Measurement setup for testing on Antenna connector	
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 1MHz, sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=1MHz, VBW = 3MHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions. 	
Test Instruments:	Refer to section 3 for details	
	Refer to section 4.1 for details	
Test mode:	Pass	







Test Procedure:	1. The EUT was placed on an non-conductive turntable using a		
	non-conductive support. The radiated emission at the fundamental		
	frequency was measured at 3 m with a test antenna and EMI		
	spectrum analyzer.		
	2. During the measurement, the EUT was communication with the		
	station. The highest emission was recorded with the rotation of the		
	turntable and the lowering of the test antenna from 4m to 1m. The		
	reading was recorded and the field strength (E in dBuV/m) was		
	calculated.		
	3. ERP were measured using a substitution method. The EUT was		
	replaced by dipole antenna connected, the S.G. output was		
	recorded and ERP was calculated asfollows:		
	ERP = S.G. output (dBm) + Antenna Gain (dBd) – Cable Loss (dB)		
	4. EIRP were measured using a substitution method. The EUTwas		
	replaced by or horn antenna connected, the S.G. output was		
	recorded and EIRP was calculated asfollows:		
	EIRP = S.G. output (dBm) + Antenna Gain (dBi) – Cable Loss (dB)		
Test Instruments:	Refer to section 3 for details		
Test mode:	Refer to section 4.1 for details		
Test results:	Pass		
Remark:	H,E1,E2 mean for EUT polarization of X, Y, Z		
Note: Please refer to Appendi	x A of the Appendix Test Data.		



	Report No.:ITEZA2-202400107RF3
4.9 FIELD STRENGTH	I OF SPURIOUS RADIATION MEASUREMENT
Test Requirement:	Part 2.1053
	Part 22.917
	Part 24.238
	Part 27.53(c)(f)
	Part 27.53(g)
	Part 27.53(h)
	Part 27.53(m)
	Part 90.691
Test Method:	ANSI C63.26:2015
Limit:	≤ -13dBm(LTE Band 5, 19, 26(824-849MHz))
	≤ -13dBm(LTE Band 2,25)
	≤ -13dBm(LTE Band 4,66)
	≤ -25dBm(LTE Band 7, 38, 41)
	≤ -13dBm(LTE Band 26(814-824MHz))
Test setup:	Below 1GHz
	Antenna Tower FUT Wind Wind Wind Wind Wind Wind Wind Wind



Report No.:ITEZA2-202400107RF3

	Ground plane Ground plane d: distance in meters d: 3 meter Same AS EUT Height S.G. Substituted Dipole or Hom Antenna Bi-Log Antenna or Hom Antenna
Test Procedure:	 The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer.
	 During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations.
	3. The frequency range up to tenth harmonic was investigated for each of three fundamental frequency(low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method.
	 The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB)
Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass



Measurement Data:

QPSK Mode:

QPSK Mode: Test mode:	LTE Band	I 2(1.4MHz)	Test channel:	Lowest
		Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3728.61	Vertical	-33.25		
5585.14	V	-35.61	-13.00	
7436.74	V	-33.05		Pass
9269.12	V	-38.74		
11128.31	V			
3728.61	Horizontal	-37.08		
5507.61	Н	-40.12		
7412.61	Н	-40.74	-13.00	Pass
9231.58	Н	-43.15		
11105.61	Н			
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Middle
	Spurious	Emission		Desult
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3728.60	Vertical	-32.52		
5627.61	V	-35.61	-13.00	Pass
7514.61	V	-35.13		
9469.61	V	-40.12		
11280.12	V		1	
3712.85	Horizontal	-36.85		
5656.31	Н	-40.18	1	
7538.14	Н	-42.81	-13.00	Pass
9412.74	Н	-40.12		
11201.71	Н			
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Highest
Fragueney (MHz)	Spurious	s Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3830.14	Vertical	-33.25		
5730.12	V	-36.13		
7656.31	V	-35.86	-13.00	Pass
9505.07	V	-40.12		
11478.32	V			
3830.14	Horizontal	-36.79		
5729.61	Н	-40.12		
7631.58	Н	-41.74	-13.00	Pass
9564.52	Н	-42.52		
11403.41	Н			

Remark :

1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2. Remark"----" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode:	LTE Band	4(1.4MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Result
3425.61	Vertical	-34.28		
5131.58	V	-33.02		
6878.61	V	-35.76	-13.00	Pass
8525.74	V	-41.01		
10201.28	V			
3410.78	Horizontal	-35.73		
5139.51	Н	-41.07		
6841.52	Н	-42.22	-13.00	Pass
8539.65	Н	-41.07		
10227.01	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle
	Spurious	Emission	Limit (dDm)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3439.84	Vertical	-33.28		Pass
5127.14	V	-35.07		
6986.59	V	-37.15	-13.00	
8651.32	V	-40.05		
10347.08	V			
3453.61	Horizontal	-37.08		Pass
5127.15	Н	-40.21		
6936.58	Н	-42.47	-13.00	
8651.28	Н	-42.01		
10301.82	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest
	Spurious	Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3512.74	Vertical	-32.76		
5209.27	V	-33.07		
7038.73	V	-34.19	-13.00	Pass
8755.01	V	-40.28		
10538.18	V			
3527.02	Horizontal	-36.68		
5260.05	Н	-40.01]	
7031.74	Н	-41.76	-13.00	Pass
8757.32	Н	-43.76	- 10.00	
10529.51	Н	l		

1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



			·	
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Lowest
	Spurious	Emission	Linsit (dDma)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1612.01	Vertical	-34.52		
2431.76	V	-37.25		
3231.27	V	-35.66	-13.00	Pass
4128.25	V	-40.12		
4945.01	V			
1793.74	Horizontal	-35.78		
2512.57	Н	-41.27		
3857.05	Н	-40.93	-13.00	Pass
4247.01	Н	-40.02		
5130.14	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MHZ)	Polarization	Level (dBm)	Liniit (dbiri)	Result
1635.61	Vertical	-33.27		Pass
2408.12	V	-34.05		
3258.65	V	-34.82	-13.00	
4272.25	V	-40.21		
5031.27	V			
4732.04	Horizontal	-35.93		
2675.58	Н	-39.62		Pass
3828.17	Н	-41.28	-13.00	
4360.27	Н	-42.27		
5130.14	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Nesul
1700.58	Vertical	-36.28	_	
2547.21	V	-37.05		
3427.07	V	-34.75	-13.00	Pass
4354.31	V	-40.12		
5131.74	V			
1733.74	Horizontal	-36.78		
2884.51	Н	-40.28	_	
3412.08	Н	-42.81	-13.00	Pass
4329.58	Н	-42.93		
5130.12	Н			

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- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



			·	
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Result
5226.31	Vertical	-33.17		
4847.25	V	-33.76		
10101.74	V	-35.01	-25.00	Pass
13578.61	V	-40.74		
15105.27	V			
5120.51	Horizontal	-35.88		
7953.74	Н	-40.13		
10127.02	Н	-41.09	-25.00	Pass
12747.21	Н	-42.75		
15120.12	Н			
Test mode:	LTE Band	1 7(5MHz)	Test channel:	Middle
	Spurious	Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5155.01	Vertical	-32.12		
7626.79	V	-35.73		Pass
10231.73	V	-34.08	-25.00	
13269.73	V	-40.76		
15508.61	V			
5112.83	Horizontal	-38.33		
7747.05	Н	-40.18		Pass
10250.31	Н	-40.72	-25.00	
13812.74	Н	-40.01		
15345.61	Н			
Test mode:	LTE Band	1 7(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MHZ)	Polarization	Level (dBm)		Result
5237.51	Vertical	-35.28		
7870.18	V	-30.15		
10355.74	V	-33.72	-25.00	Pass
12908.61	V	-41.02		
15313.32	V			
5208.61	Horizontal	-36.64		
7747.31	Н	-40.05]	
10329.65	Н	-41.74	-25.00	Pass
12713.27	Н	-42.88]	
15346.02	Н]	

1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode:	LTE Band	19(5MHz)	Test channel:	Lowest
	Spurious	Emission	Linsit (dDno)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1359.61	Vertical	-33.25		
2682.14	V	-38.76		
3357.58	V	-34.02	-13.00	Pass
4204.31	V	-38.71		
4936.24	V			
1389.38	Horizontal	-34.05		
2513.02	Н	-40.01		
3614.75	Н	-38.28	-13.00	Pass
4263.27	Н	-37.01		
5129.51	Н			
Test mode:	LTE Band	19(5MHz)	Test channel:	Middle
	Spurious	Emission	Limit (dDm)	Deput
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1534.21	Vertical	-32.02		
2634.75	V	-37.05		Pass
3457.28	V	-35.06	-13.00	
4305.76	V	-40.07		
5127.58	V			
4827.02	Horizontal	-33.85		
2564.01	Н	-36.58		Pass
3927.52	Н	-40.21	-13.00	
4271.2	Н	-41.32		
5347.12	Н			
Test mode:	LTE Band	19(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MITZ)	Polarization	Level (dBm)		Result
1523.74	Vertical	-37.29		
2304.52	V	-36.02		
3593.21	V	-35.12	-13.00	Pass
4405.74	V	-39.27		
5276.28	V			
1727.01	Horizontal	-35.02		
2876.12	Н	-39.22	-13.00	
3538.51	Н	-41.02		Pass
4347.02	Н	-41.74		
5129.51	Н			



Test mode:	LTE Band	25(5MHz)	Test channel:	Lowest
	Spurious	Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5131.74	Vertical	-34.76		
7624.02	V	-35.21		
10131.79	V	-36.90	-13.00	Pass
12247.02	V	-37.08		
15202.13	V			
5031.04	Horizontal	-38.31		
7549.33	Н	-37.05		
10531.05	Н	-36.27	-13.00	Pass
12556.65	Н	-39.61		
15223.75	Н			
Test mode:	LTE Band	25(5MHz)	Test channel:	Middle
	Spurious	Emission	Lineit (dDne)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5249.21	Vertical	-33.02		
7628.75	V	-33.12		Pass
10233.21	V	-32.79	-13.00	
12527.27	V	-38.01		
15385.64	V			
5202.31	Horizontal	-32.74		
7529.61	Н	-33.07		
10238.52	Н	-40.25	-13.00	Pass
13527.05	Н	-41.74		
15301.31	Н			
Test mode:	LTE Band	25(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	Linin (dbiri)	rtooun
5208.61	Vertical	-32.02		
7849.25	V	-35.98		
10019.35	V	-32.15	-13.00	Pass
12221.05	V	-40.12		
15376.28	V			
5289.25	Horizontal	-38.31		
7833.28	Н	-39.62]	
10376.02	Н	-40.71	-13.00	Pass
12201.52	Н	-40.18		
15309.25	Н			

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Test mode(814-824MHz):		Band 26(5MHz)	Test channel:	Lowest
Frequency (MHz)		urious Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	()	
3427.61	Vertical	-33.27	-	
7804.85	V	-35.76	_	
10138.14	V	-32.01	-13.00	Pass
12301.01	V	-40.12		
16214.52	V			
5175.25	Horizontal	-32.12		
7629.61	Н	-40.15		
10235.15	Н	-41.75	-13.00	Pass
12527.51	Н	-40.25		
15201.52	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Erequency (MHz)	Sp	urious Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5128.61	Vertical	-31.08		
7629.65	V	-32.78	-13.00	Pass
10254.76	V	-33.56		
13263.76	V	-37.85		
15521.52	V			
5218.85	Horizontal	-33.07		
7708.72	Н	-34.12		
10256.78	Н	-40.53	-13.00	Pass
12596.31	Н	-41.29		
15250.76	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
Fraguanay (MHz)	Sp	urious Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5225.39	Vertical	-35.12		
7813.23	V	-33.74		
10356.28	V	-35.85	-13.00	Pass
12853.72	V	-38.13]	
15315.85	V			
5125.17	Horizontal	-36.13		
7832.85	Н	-38.85]	
10315.74	Н	-39.61	-13.00	Pass
12932.28	Н	-41.57	1	
15252.75	Н		1	

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2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
_	Sp	urious Emission		
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3912.58	Vertical	-34.08		
5689.31	V	-33.07		
10258.61	V	-32.74	-13.00	Pass
12279.61	V	-40.12		
13398.05	V			
3827.61	Horizontal	-38.63		
7276.31	Н	-37.85		
10278.65	Н	-41.05	-13.00	Pass
12057.25	Н	-42.74		
13325.58	Н			
fest mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fraguanay (MHz)	Sp	urious Emission	Limit (dPm)	Popult
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3689.12	Vertical	-33.89		
7896.13	V	-33.05	-13.00	Pass
10458.28	V	-32.72		
12017.82	V	-39.68		
15759.58	V			
3827.35	Horizontal	-35.79		
7593.02	Н	-40.02		
10458.91	Н	-40.12	-13.00	Pass
12468.58	Н	-41.86		
15318.62	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
Frequency (MHz)	Sp	urious Emission	Limit (dBm)	Result
r requency (mrrz)	Polarization	Level (dBm)		Result
3863.21	Vertical	-30.96		
7817.02	V	-30.01		
10458.61	V	-34.89	-13.00	Pass
12325.74	V	-40.12		
15489.25	V			
3886.01	Horizontal	-33.89		
7847.05	Н	-37.08		
10429.58	Н	-41.05	-13.00	Pass
12318.85	Н	-42.85		
15269.85	Н			

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Test mode		Band 38(5MHz)	Test channel:	Lowest
Frequency (MHz)	· · · · · ·	urious Emission	Limit (dBm)	Result
0000 40	Polarization	Level (dBm)		
2626.12	Vertical	-33.23	-	
5242.01	V	-35.84		_
10571.43	V	-33.26	-25.00	Pass
12201.55	V	-39.99	_	
13568.92	V			
2624.64	Horizontal	-38.1	_	
5241.23	Н	-39.8	_	
10824.19	Н	-42.64	-25.00	Pass
12239.03	Н	-43.74	_	
13246.38	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Middle
Frequency (MHz)	Spu	rious Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	Linit (dbin)	Result
2755.93	Vertical	-31.03		
5470.22	V	-37.5		
10646.18	V	-33.75	-25.00	Pass
12851.16	V	-41.97		
15581.06	V			
2669.64	Horizontal	-37.83		
5444.76	Н	-38.59		
10812.23	Н	-42.10	-25.00	Pass
12244.23	Н	-42.72		
15313.03	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Highest
Frequency (MHz)	Spι	rious Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Nesuit
2623.74	Vertical	-32.50		
6880.23	V	-37.13		
10446.22	V	-33.23	-25.00	Pass
12711.03	V	-39.83		
15509.43	V			
2671.24	Horizontal	-33.10		
5200.43	Н	-38.61		
10733.12	Н	-42.10	-25.00	Pass
13242.12	Н	-43.10	7	
16242.65	Н		7	

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Test mode	LTE	Band 41(5MHz)	Test channel:	Lowest
	Spu	rious Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3673.03	Vertical	-30.44		
8619.91	V	-37.23		
10239.23	V	-36.26	-25.00	Pass
12646.53	V	-40.175		
13246.52	V			
3973.23	Horizontal	-36.55		
9819.16	Н	-40.54		
10245.03	Н	-42.41	-25.00	Pass
12252.23	Н	-41.41		
13146.56	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Middle
	Spu	rious Emission	Linsit (dDms)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3574.77	Vertical	-33.25		
5961.91	V	-36.89		
8951.12	V	-35.27	-25.00	Pass
10223.03	V	-40.02		
13673.77	V			
5851.73	Horizontal	-34.58		
7244.03	Н	-42.73		
10313.3	Н	-40.12	-25.00	Pass
12239.64	Н	-33.15		
13244.16	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Highest
Frequency (MHz)	Spu	rious Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	Liniit (ubin)	Result
3113.22	Vertical	-35.61		
5623.03	V	-37.62		
8950.12	V	-36.25	-25.00	Pass
10346.53	V	-40.12		
12747.76	V			
5113.78	Horizontal	-37.52		
8683.67	Н	-40.12		
10274.22	Н	-41.05	-25.00	Pass
12645.03	Н	-42.85		
13574.23	Н			

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			•	
Test mode:	LTE Band 6	6(1.4MHz)	Test channel:	Lowest
Frequency	Spurious	Spurious Emission		
(MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3313.43	Vertical	-33.26		
5674.76	V	-37.36		
7313.2	V	-34.56	-13.00	Pass
8284.22	V	-40.87		
10313.26	V			
3316.66	Horizontal	-37.83		
5239.16	Н	-40.41		
6923.03	Н	-42.71	-13.00	Pass
8851.12	Н	-43.56		
10252.03	Н			
Test mode:	LTE Band 6	6(1.4MHz)	Test channel:	Middle
Frequency	Spurious	Emission	Limit (dBm)	Result
(MHz)	Polarization	Level (dBm)	Linit (dBin)	Result
2884.22	Vertical	-37.73		
5356.59	V	-38.97	-13.00	
7524.12	V	-37.51		Pass
9851.03	V	-41.23		
10240.16	V			
3003.73	Horizontal	-37.83		
5244.01	Н	-39.83		
7623.76	Н	-42.16	-13.00	Pass
8820.66	Н	-42.30		
10383.02	Н			
Test mode:	LTE Band 6	6(1.4MHz)	Test channel:	Highest
Frequency	Spurious	Emission	Limit (dBm)	Result
(MHz)	Polarization	Level (dBm)		Result
3746.52	Vertical	-33.84		
5300.16	V	-32.10		
7241.05	V	-35.87	-13.00	Pass
8616.56	V	-43.10		
10446.22	V			
3317.52	Horizontal	-37.83		
5300.65	Н	-42.27		
7300.63	Н	-43.03	-13.00	Pass
8814.22	Н	-43.45		
10110.48	Н			

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The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst



16 QAM Mode:				
Test mode:	LTE Band 2 (1.4MHz)		Test channel:	Lowest
Frequency (MHz)	Spurious Emission		Limit (dBm)	Result
,	Polarization	Level (dBm)		
3519.32	Vertical	-33.19	_	Pass
5682.22	V	-35.60		
8619.38	V	-34.83	-13.00	
9686.62	V	-40.50	_	
11352.11	V			
3613.05	Horizontal	-33.84		Pass
5577.22	Н	-38.59		
7686.69	Н	-42.72	-13.00	
9356.76	Н	-42.10		
12352.12	Н			
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Middle
	Spurious	Emission	Line it (dDne)	Desult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3856.96	Vertical	-33.72		Pass
5819.03	V	-35.83		
7920.69	V	-34.10	-13.00	
9346.22	V	-40.83		
12112.46	V			
3316.52	Horizontal	-37.83		Pass
5566.11	Н	-40.51		
7919.66	Н	-42.85	-13.00	
9881.03	Н	-43.83		
11300.19	Н			
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Highest
	Spurious			Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
2884.75	Vertical	-33.49		
5619.16	V	-38.56	1	Pass
7849.14	V	-36.83	-13.00	
9264.69	V	-36.10		
12140.76	V			
3751.54	Horizontal	-37.83		
5686.38	H	-40.26	-13.00	Pass
7519.02	H	-40.20		
9474.5	H	-42.15		1 000
3414.0	11	-42.10		

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Test mode:	LTE Band 4(1.4MHz)		Test channel:	Lowest
	Spurious Emission		Limit (dPm)	D It
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
3403.12	Vertical	-33.26		
5242.45	V	-36.87		Pass
6312.19	V	-32.10	-13.00	
8671.22	V	-43.56		
11242.16	V			
3313.84	Horizontal	-35.59		Pass
4951.22	Н	-39.59		
7677.19	Н	-42.79	-13.00	
9619.16	Н	-43.85		
10373.65	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle
	Spurious	Emission	Limit (dDm)	Desult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3277.52	Vertical	-37.80		
5242.76	V	-36.29		Pass
7317.22	V	-35.72	-13.00	
8949.16	V	-40.50		
10244.03	V			
3347.26	Horizontal	-37.72		Pass
5245.63	Н	-38.19		
6857.22	Н	-42.72	-13.00	
9316.49	Н	-41.00		
10413.63	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (IVIEZ)	Polarization	Level (dBm)	Limit (dBm)	Result
3222.49	Vertical	-35.59	-13.00	Pass
5113.75	V	-37.57		
8620.03	V	-32.82		
9524.66	V	-42.83		
11253.63	V			
3500.8	Horizontal	-36.26		
5356.72	Н	-39.54	-13.00	
7244.65	Н	-42.79		Pass
8924.48	Н	-40.26		
10316.65	Н			

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Test mode:	LTE Band 5(1.4MHz)		Test channel:	Lowest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
,	Polarization	Level (dBm)		Rooun
1951.03	Vertical	-36.83		Pass
2504.22	V	-37.21		
3635.42	V	-38.22	-13.00	
4222.65	V	-40.43		
5627.03	V			
1637.76	Horizontal	-35.96		
2461.76	Н	-40.44		
3287.03	Н	-42.72	-13.00	Pass
4239.79	Н	-43.10		
5036.65	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle
Fraguenov (MHz)	Spurious	Emission	Limit (dPm)	Deput
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1671.03	Vertical	-35.56		Pass
2500.46	V	-35.10		
3446.47	V	-38.30	-13.00	
4187.16	V	-41.36		
5111.76	V			
1550.03	Horizontal	-38.03		Pass
2300.76	Н	-41.75		
3443.79	Н	-43.10	-13.00	
4171.27	Н	-45.29		
5516.65	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Highest
	Spurious	Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
1157.76	Vertical	-37.56		
2347.03	V	-33.10]	Pass
3220.78	V	-32.83	-13.00	
4213.83	V	-40.10	1	
5113.65	V		1	
1663.16	Horizontal	-33.19		
2531.63	Н	-32.50	-13.00	
3386.19	Н	-40.82		Pass
4231.36	Н	-40.39		
5077.76	Н			

1 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured

Test mode:	LTE Band	19(5MHz)	Test channel:	Lowest
	Spurious	Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
1963.68	Vertical	-35.56		
2516.87	V	-35.94		Pass
3648.07	V	-36.95	-13.00	
4235.30	V	-39.16		
5639.68	V			
1650.41	Horizontal	-34.69		Pass
2474.41	Н	-39.17		
3299.68	Н	-41.45	-13.00	
4252.44	Н	-41.83		
5049.30	Н		1	
Test mode:	LTE Band	19(5MHz)	Test channel:	Middle
	Spurious	Emission		Data II
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
1683.68	Vertical	-34.29		Pass
2513.11	V	-33.83	-13.00	
3459.12	V	-37.03		
4199.81	V	-40.09		
5124.41	V			
1562.68	Horizontal	-36.76		Pass
2313.41	Н	-40.48		
3456.44	Н	-41.83	-13.00	
4183.92	Н	-44.02		
5529.30	Н			
Test mode:	LTE Band	19(5MHz)	Test channel:	Highest
- (1411)	Spurious	Emission		-
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1170.41	Vertical	-36.29		
2359.68	V	-31.83		Pass
3233.43	V	-31.56	-13.00	
4226.48	V	-38.83	-	
5126.30	V		1	
1675.81	Horizontal	-31.92		
2544.28	Н	-31.23	1	
3398.84	Н	-39.55	-13.00	Pass
4244.01	Н	-39.12		
5090.41	Н			

4 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode:	LTE Band 7(5MHz)		Test channel:	Lowest
	Spurious Emission			2011001
Frequency (MHz)	Polarization	Level (dBm)	– Limit (dBm)	Result
5138.16	Vertical	-31.98		Pass
7341.39	V	-35.74		
9053.41	V	-34.35	-25.00	
12378.39	V	-39.14		
15371.51	V			
5138.64	Horizontal	-32.31	1	Pass
7341.26	Н	-38.25		
9643.90	Н	-40.85	-25.00	
12469.16	Н	-42.58		
15281.41	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Middle
	Spurious	Emission		Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
5137.96	Vertical	-31.98		
7702.17	V	-34.69		Pass
10140.66	V	-38.58	-25.00	
12672.42	V	-41.17		
15241.08	V			
5141.27	Horizontal	-37.94		Pass
7639.89	Н	-41.57		
10271.88	Н	-40.47	-25.00	
12328.39	Н	-42.01		
15341.50	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Nesuit
5040.96	Vertical	-34.08	-25.00	Pass
7851.50	V	-35.88		
10327.79	V	-32.29		
12975.93	V	-39.74		
15644.39	V			
5142.26	Horizontal	-32.31	-25.00	
7845.51	Н	-39.47		
10213.90	Н	-43.68		Pass
12876.13	Н	-44.05		
15514.17	Н			

1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode:	LTE Band 25(5MHz)		Test channel:	Lowest	
	Spurious	Emission	Line it (JDne)	Decult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
5140.96	Vertical	-31.54			
7372.39	V	-36.25			
10141.50	V	-34.57	-13.00	Pass	
12252.39	V	-38.98			
13513.93	V				
5148.44	Horizontal	-36.58			
7541.67	Н	-39.48			
10138.39	Н	-41.58	-13.00	Pass	
12033.70	Н	-40.85			
13540.96	Н				
Test mode:	LTE Band	25(5MHz)	Test channel:	Middle	
	Spurious	Emission	Limit (dDm)	Decult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
5038.50	Vertical	-31.98		Pass	
7296.16	V	-31.58			
10041.50	V	-34.34	-13.00		
12704.39	V	-39.47			
15465.90	V				
5061.50	Horizontal	-35.47			
7643.90	Н	-41.47			
10264.41	Н	-38.96	-13.00	Pass	
12034.23	Н	-42.47			
15470.90	Н				
Test mode:	LTE Band	25(5MHz)	Test channel:	Highest	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
	Polarization	Level (dBm)		Nesuit	
5215.86	Vertical	-30.85			
7740.77	V	-32.58			
10264.86	V	-36.58	-13.00	Pass	
12724.66	V	-38.85			
15465.39	V				
5225.50	Horizontal	-35.57			
7793.50	Н	-38.38			
10286.04	Н	-41.47	-13.00	Pass	
12727.90	Н	-41.85			
15536.29	Н				

4 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

- 5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 6 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
	Spurious Emission			
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3258.27	Vertical	-32.24		
7258.26	V	-31.47		
10138.10	V	-30.01	-13.00	Pass
12465.39	V	-41.47		
15141.02	V			
3671.12	Horizontal	-35.57		
7540.96	Н	-38.87		
10101.98	Н	-41.47	-13.00	Pass
12499.23	Н	-41.87		
15140.93	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fraguanay (MHz)	Spi	urious Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5039.86	Vertical	-30.85		
7641.95	V	-32.59		Pass
10338.40	V	-34.34	-13.00	
12700.44	V	-40.01		
15330.93	V			
5138.41	Horizontal	-35.62		
7226.70	Н	-39.57		
10267.43	Н	-41.48	-13.00	Pass
12738.54	Н	-42.58		
15337.90	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
Frequency (MHz)	Spu	urious Emission	Limit (dBm)	Result
Frequency (Miriz)	Polarization	Level (dBm)	Limit (dBm)	Result
5225.43	Vertical	-32.01		
7741.86	V	-34.27		
10327.17	V	-33.78	-13.00	Pass
12866.67	V	-41.47		
15549.11	V			
5314.23	Horizontal	-35.58		
7842.06	Н	-39.47		
10171.08	Н	-41.20	-13.00	Pass
12849.13	Н	-42.78		
15342.44	Н			

4 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
Frequency (MHz)	Sp	Spurious Emission		D It
	Polarization	Level (dBm)	Limit (dBm)	Result
3925.16	Vertical	-34.41		
7649.23	V	-36.54		
10058.26	V	-35.62	-13.00	Pass
12599.17	V	-39.47		
13608.98	V			
3949.49	Horizontal	-36.58		
7674.50	Н	-41.87		
10138.39	Н	-41.47	-13.00	Pass
12325.39	Н	-42.47		
13299.77	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
	Sp	urious Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3825.23	Vertical	-34.57		
7649.39	V	-31.85		
10338.39	V	-31.47	-13.00	Pass
12488.32	V	-39.47		
15398.38	V			
3825.39	Horizontal	-37.58		
7623.23	Н	-38.58		
10371.39	Н	-41.27	-13.00	Pass
12741.10	Н	-39.47		
15371.21	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
	Sp	urious Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3771.26	Vertical	-35.47		
7849.50	V	-34.47		
10328.39	V	-35.74	-13.00	Pass
12482.81	V	-39.47		
15537.73	V			
3839.90	Horizontal	-36.58		
7823.39	Н	-38.58		
10244.06	Н	-41.47	-13.00	Pass
12517.92	Н	-39.78		
15267.08	Н			

4 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.

5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode	LTE	Band 38(5MHz)	Test channel:	Lowest
		rious Emission		Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
2377.01	Vertical	-32.75		
5289.06	V	-37.47		
10261.26	V	-37.47	-25.00	Pass
12906.15	V	-40.58		
13496.10	V			
3115.23	Horizontal	-36.58		
5289.59	Н	-40.88		
10040.36	Н	-39.58	-25.00	Pass
12770.96	Н	-44.59		
13040.23	Н			
Test mode	LTE E	Band 38(5MHz)	Test channel:	Middle
Fraguanay (MHz)	Spur	rious Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2599.02	Vertical	-33.58		
5287.06	V	-35.98	-25.00	Pass
10586.77	V	-34.69		
12770.50	V	-39.75		
15644.54	V			
2580.95	Horizontal	-32.47		
5260.00	Н	-39.48		
10874.17	Н	-41.11	-25.00	Pass
12382.07	Н	-44.85		
15469.66	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Highest
Frequency (MHz)	Spur	rious Emission	Limit (dBm) Resul	
	Polarization	Level (dBm)		Result
2591.39	Vertical	-34.64		
5771.30	V	-36.75		
10669.69	V	-36.58	-25.00	Pass
12694.79	V	-41.58		
16291.19	V			
2642.51	Horizontal	-37.46		
5514.29	Н	-40.85		
10288.39	Н	-42.47	-25.00	Pass
13010.39	Н	-41.75		
16393.93	н			

4 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode	LTE	Band 41(5MHz)	Test channel:	Lowest
- (111)	Spurious Emission			
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
4848.77	Vertical	-35.05		
9943.70	V	-34.49		
10266.78	V	-32.98	-25.00	Pass
12300.01	V	-40.47		
13041.10	V			
4921.03	Horizontal	-34.57		
9923.40	Н	-42.46		
10113.00	Н	-39.45	-25.00	Pass
12581.67	Н	-41.47		
13230.90	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Middle
Frequency (MHz)	Spu	rious Emission	Limit (dBm)	Result
Frequency (Minz)	Polarization	Level (dBm)		Result
5086.70	Vertical	-34.56		
10023.00	V	-35.75		Pass
12231.08	V	-35.55	-25.00	
13470.51	V	-38.84		
15330.95	V			
5051.32	Horizontal	-35.66		
10136.70	Н	-38.74		
12471.00	Н	-41.58	-25.00	Pass
13266.67	Н	-40.47		
15483.85	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Highest
Frequency (MHz)	Spu	rious Emission	Limit (dBm)	Result
	Polarization	Level (dBm)		Result
5138.03	Vertical	-34.75		
10160.02	V	-36.25		
12135.67	V	-31.74	-25.00	Pass
13254.01	V	-39.47		
15271.03	V			
5026.98	Horizontal	-35.71		
10338.43	Н	-40.00		
12764.06	Н	-41.08	-25.00	Pass
13606.28	Н	-41.78		
15266.86	Н			

4 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured



Test mode:	LTE Band 66(1.4MHz)		Test channel:	Lowest	
	Spurious Emission				
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3425.86	Vertical	-32.58			
5248.89	V	-36.25			
6718.26	V	-32.45	-13.00	Pass	
8341.12	V	-39.74			
10234.39	V				
3425.44	Horizontal	-35.62			
5218.39	Н	-38.29			
6870.50	Н	-40.58	-13.00	Pass	
8548.82	Н	-42.58			
10285.90	Н				
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Middle	
	Spurious	Emission	Limit (dDm)	D It	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3446.29	Vertical	-34.78			
5137.83	V	-34.58			
6951.48	V	-35.85	-13.00	Pass	
8734.17	V	-38.78			
10363.66	V				
3340.95	Horizontal	-34.47			
5267.61	Н	-39.52			
6951.86	Н	-40.74	-13.00	Pass	
8715.53	Н	-41.47			
10595.78	Н				
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Highest	
Frequency (MHz)	Spurious Emission		Limit (dBm)	Result	
	Polarization	Level (dBm)		Result	
3341.26	Vertical	-31.47			
5136.39	V	-29.81			
7051.92	V	-31.78	-13.00	Pass	
8714.93	V	-40.58			
10546.54	V				
3545.77	Horizontal	-35.58			
5284.51	Н	-35.75			
7043.67	Н	-40.85	-13.00	Pass	
8805.93	Н	-42.58			
0000100					

1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.

- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test Descriptions of		
Test Requirement:	Part 2.1055(a)(1)(b), Part 22.355	
	Part 24.235 , Part 27.54, Part 90.213	
Test Method:	ANSI C63.26:2015	
Limit:	2.5ppm(Part 22)	
	Within the authorized bands of operation(Part 24, Part 27)	
Test setup:	Temperature Chamber	
	Spectrum analyzer EUT	
	Variable Power Supply Note: Measurement setup for testing on Antenna connector	
Test procedure:	 The equipment under test was connected to an external DC power supply and input rated voltage. RF output was connected to a frequency counter or spectrum analyzer via feed through attenuators. The EUT was placed inside the temperature chamber. Set the spectrum analyzer RBW low enough to obtain the desire frequency resolution and measure EUT 25°C operating frequence as reference frequency. Turn EUT off and set the chamber temperature to -20°C. After th temperature stabilized for approximately 30 minutes recorded th frequency. Repeat step measure with 10°C increased per stage until th highest temperature of +50°C reached. 	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	
Remark:	If all frequencies stability are comply with the lower limit, then all result	



4.11 FREQUENCY STABILITY V.S. VOLTAGE MEASUREMENT		
Test Requirement:	Part 2.1055(d)(1)(2) Part 22.355 Part 24.235 Part 27.54	
	Part 90.213	
Test Method:	ANSI C63.26:2015	
Limit:	2.5ppm	
	Band II & Band VII should be within authorized band.	
Test setup:	Temperature Chamber	
Test procedure:	Spectrum analyzer Att. UT EUT EUT L Variable Power Supply Note : Measurement setup for testing on Antenna connector 1. Set chamber temperature to 20°C. Use a variable DC power source to power the EUT and set the voltage to rated voltage. 2. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency.	
	 Reduce the input voltage to specified extreme voltage variation (+/- 15%) and endpoint, record the maximum frequency change. 	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	
Remark:	1. Manufacturer specified the battery operating end point voltage is	
	3.61VDC, max voltage is 4.18VDC.	
	2. If all frequencies stability are comply with the lower limit, then all	
Note: Please refer to Appendix Fof	results can be considered qualified	

Note: Please refer to Appendix Fof the Appendix Test Data.



